ANALOG DEVICES

1 pF Off Capacitance, 1 pC Charge Injection, ±15 V/12 V *i*CMOS™ Quad SPST Switches

Preliminary Technical Data

ADG1211/ADG1212/ADG1213

FEATURES

2 pF off capacitance
1 pC charge injection
33 V supply range
150 Ω on resistance
Fully specified at +12 V, ±15 V
No V_L supply required
3 V logic-compatible inputs
Rail-to-rail operation
16-lead TSSOP and 16-lead LFCSP packages
Typical power consumption: <0.03 µW

APPLICATIONS

Automatic test equipment
Data aquisition systems
Battery-powered systems
Sample-and-hold systems
Audio signal routing
Video signal routing
Communication systems

GENERAL DESCRIPTION

The ADG1211/ADG1212/ADG1213 are monolithic CMOS devices containing four independently selectable switches designed on an *i*CMOS process. *i*CMOS (industrial-CMOS) is a modular manufacturing process combining high voltage CMOS (complementary metal-oxide semiconductor) and bipolar technologies. It enables the development of a wide range of high performance analog ICs capable of 30 V operation in a footprint that no previous generation of high voltage parts has been able to achieve. Unlike analog ICs using conventional CMOS processes, *i*CMOS components can tolerate high supply voltages, while providing increased performance, dramatically lower power consumption, and reduced package size.

The ultralow capacitance and charge injection of these switches make them ideal solutions for data acquisition and sample-and-hold applications, where low glitch and fast settling are required. Fast switching speed coupled with high signal bandwidth make the parts suitable for video signal switching.

FUNCTIONAL BLOCK DIAGRAM
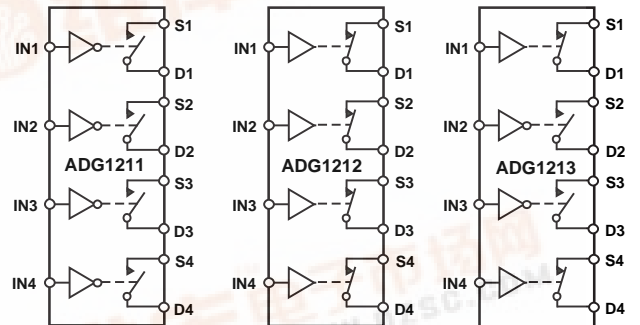
SWITCHES SHOWN FOR A LOGIC 1 INPUT

Figure 1.

*i*CMOS construction ensures ultralow power dissipation, making the parts ideally suited for portable and battery-powered instruments.

The ADG1211/ADG1212/ADG1213 contain four independent single-pole/single-throw (SPST) switches. The ADG1211 and ADG1212 differ only in that the digital control logic is inverted. The ADG1211 switches are turned on with Logic 0 on the appropriate control input, while Logic 1 is required for the ADG1212. The ADG1213 has two switches with digital control logic similar to that of the ADG1211; the logic is inverted on the other two switches. Each switch conducts equally well in both directions when on, and has an input signal range that extends to the supplies. In the off condition, signal levels up to the supplies are blocked.

The ADG1213 exhibits break-before-make switching action for use in multiplexer applications. Inherent in the design is low charge injection for minimum transients when switching the digital inputs.

PRODUCT HIGHLIGHTS

1. 2 pF off capacitance (±15 V supply).
2. 1 pC charge injection.
3. 3 V logic-compatible digital inputs: V_{IH} = 2.0 V, V_{IL} = 0.8 V.
4. No V_L logic power supply required.
5. Ultralow power dissipation: <0.03 µW.
6. 16-lead TSSOP and 4 mm × 4 mm LFCSP packages.

TABLE OF CONTENTS

REVISION HISTORY

11/04—Revision PrE: Preliminary Version

SPECIFICATIONS

SINGLE SUPPLY

V_{DD} = 15 V ± 10%, V_{SS} = −15 V, GND = 0 V, unless otherwise noted.

Table 1.

Parameter	25°C	85°C	Y Version[1]	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range			V_{DD} to V_{SS}	V	
On Resistance (R_{ON})	120	160	180	Ω typ	V_S = ±10 V, I_S = −10 mA; Figure 20
				Ω max	
On Resistance Match between Channels (ΔR_{ON})	5			Ω typ	V_S = ±10 V , I_S = −10 mA
				Ω max	
On Resistance Flatness ($R_{FLAT(ON)}$)	25			Ω typ	V_S = −5 V/0 V/+5 V; I_S = −10 mA
			50	Ω max	
LEAKAGE CURRENTS					V_{DD} = +10 V, V_{SS} = −10 V
Source Off Leakage, I_S (Off)	±0.01			nA typ	V_S = 0 V/10 V, V_D = 10 V/0 V; Figure 21
	±0.5	±1	±5	nA max	
Drain Off Leakage, I_D (Off)	±0.01			nA typ	V_S = 0 V/10 V, V_D = 10 V/0 V; Figure 21
	±0.5	±1	±5	nA max	
Channel On Leakage, I_D, I_S (On)	±0.04			nA typ	V_S = V_D = 0 V or 10 V; Figure 22
	±1	±2	±5	nA max	
DIGITAL INPUTS					
Input High Voltage, V_{INH}			2.0	V min	
Input Low Voltage, V_{INL}			0.8	V max	
Input Current, I_{INL} or I_{INH}	0.005		±2.5	µA typ	V_{IN} = V_{INL} or V_{INH}
			±0.5	µA max	
Digital Input Capacitance, C_{IN}	5			pF typ	
DYNAMIC CHARACTERISTICS[2]					
t_{ON}	50			ns typ	R_L = 300 Ω, C_L = 35 pF
				ns max	V_S = ±10 V; Figure 23
t_{OFF}	15			ns typ	R_L = 300 Ω, C_L = 35 pF
				ns max	V_S = ±10 V; Figure 23
Break-before-Make Time Delay, t_D	15			ns typ	R_L = 300 Ω, C_L = 35 pF
			1	ns min	V_{S1} = V_{S2} = 10 V; Figure 24
Charge Injection	1			pC typ	V_S = 0 V, R_S = 0 Ω, C_L = 1 nF; Figure 25
Off Isolation	75			dB typ	R_L = 50 Ω, C_L = 5 pF, f = 1 MHz; Figure 26
Channel-to-Channel Crosstalk	85			dB typ	R_L = 50 Ω, C_L = 5 pF, f = 1 MHz; Figure 27
Total Harmonic Distortion + Noise	0.002			% typ	R_L = 600 Ω, 5 V rms, f = 20 Hz to 20 kHz
−3 dB Bandwidth	700			MHz typ	R_L = 50 Ω, C_L = 5 pF; Figure 28
C_S (Off)	2			pF typ	
C_D (Off)	2			pF typ	
C_D, C_S (On)	4			pF typ	
POWER REQUIREMENTS					V_{DD} = +16.5 V, V_{SS} = −16.5 V
I_{DD}	0.001			µA typ	Digital Inputs = 0 V or V_{DD}
			5.0	µA max	
I_{DD}	0.001			µA typ	Digital Inputs = 5 V
			5.0	µA max	
I_{SS}	0.001			µA typ	Digital Inputs = 0 V or V_{DD}
			5.0	µA max	

Parameter	25°C	85°C	Y Version[1]	Unit	Test Conditions/Comments
I_{GND}	0.001			µA typ	Digital Inputs = 0 V or V_{DD}
			5.0	µA max	
I_{GND}	0.001			µA typ	Digital Inputs = 5 V
			5.0	µA max	

[1] Temperature range for Y Version is −40°C to +125°C.
[2] Guaranteed by design, not subject to production test.

V_{DD} = 12 V ± 10%, V_{SS} = 0 V, GND = 0 V, unless otherwise noted.

Table 2.

Parameter	25°C	85°C	Y Version[1]	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range			0 V to V_{DD}	V	
On Resistance (R_{ON})	220	250		Ω typ	V_S = +10 V, I_S = −10 mA; Figure 20
				Ω max	
On Resistance Match between Channels (ΔR_{ON})	1			Ω typ	V_S = +10 V, I_S = −10 mA
				Ω max	
On -Resistance Flatness ($R_{FLAT(ON)}$)	12			Ω typ	V_S = −5 V/0 V/+5 V, I_S = −10 mA
LEAKAGE CURRENTS					V_{DD} = 12 V
Source Off Leakage, I_S (Off)	±0.01			nA typ	V_S = 1 V/10 V, V_D = 10 V/0 V; Figure 21
	±0.5		±2.5	nA max	
Drain Off Leakage, I_D (Off)	±0.01			nA typ	V_S = 1 V/10 V, V_D = 10 V/0 V; Figure 21
	±0.5		±2.5	nA max	
Channel On Leakage, I_D, I_S (On)	±0.04			nA typ	V_S = V_D = 1 V or 10 V; Figure 22
	±1		±5	nA max	
DIGITAL INPUTS					
Input High Voltage, V_{INH}			2.0	V min	
Input Low Voltage, V_{INL}			0.8	V max	
Input Current, I_{INL} or I_{INH}	0.001			µA typ	V_{IN} = V_{INL} or V_{INH}
			±0.5	µA max	
Digital Input Capacitance, C_{IN}	5			pF typ	
DYNAMIC CHARACTERISTICS[2]					
t_{ON}	50			ns typ	R_L = 300 Ω, C_L = 35 pF
				ns max	V_S = 8 V; Figure 23
t_{OFF}	15			ns typ	R_L = 300 Ω, C_L = 35 pF
				ns max	V_S = 8 V; Figure 23
Break-before-Make Time Delay, t_D	15			ns typ	R_L = 300 Ω, C_L = 35 pF
			1	ns min	V_{S1} = V_{S2} = 8 V; Figure 24
Charge Injection	5			pC typ	V_S = 0 V, R_S = 0 Ω, C_L = 1 nF; Figure 25
Off Isolation	75			dB typ	R_L = 50 Ω, C_L = 5 pF, f = 1 MHz; Figure 267
Channel-to-Channel Crosstalk	85			dB typ	R_L = 50 Ω, C_L = 5 pF, f = 1 MHz; Figure 27
−3 dB Bandwidth	100			MHz typ	R_L = 50 Ω, C_L = 5 pF; Figure 28
C_S (Off)	2			pF typ	
C_D (Off)	2			pF typ	
C_D, C_S (On)	4			pF typ	

Parameter	25°C	85°C	Y Version[1]	Unit	Test Conditions/Comments
POWER REQUIREMENTS					V_{DD} = 13.2 V
I_{DD}	0.001			µA typ	Digital Inputs = 0 V or V_{DD}
			5.0	µA max	
I_{DD}	0.001			µA typ	Digital Inputs = 5 V
			5.0	µA max	

[1] Temperature range for Y Version is −40°C to +125°C.
[2] Guaranteed by design, not subject to production test.

ABSOLUTE MAXIMUM RATINGS

T_A = 25°C, unless otherwise noted.

Table 3.

Parameter	Rating
V_{DD} to V_{SS}	35 V
V_{DD} to GND	−0.3 V to +25 V
V_{SS} to GND	+0.3 V to −25 V
Analog Inputs[1]	V_{SS} – 0.3 V to V_{DD} + 0.3 V
Digital Inputs[1]	GND – 0.3 V to V_{DD} + 0.3 V or 30 mA, whichever occurs first
Peak Current, S or D	100 mA (pulsed at 1 ms, 10% duty cycle max)
Continuous Current, S or D	30 mA
Operating Temperature Range	
Industrial (B Version)	−40°C to +85°C
Automotive (Y Version)	−40°C to +125°C
Storage Temperature Range	−65°C to +150°C
Junction Temperature	150°C
16-Lead TSSOP, θ_{JA} Thermal Impedance	150.4°C/W
16-Lead LFCSP, θ_{JA} Thermal Impedance	30.4°C/W
Lead Temperature, Soldering	
Vapor Phase (60 s)	215°C
Infrared (15 s)	220°C

[1] Overvoltages at IN, S, or D are clamped by internal diodes. Current should be limited to the maximum ratings given.

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those listed in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Only one absolute maximum rating may be applied at any one time.

Table 4. ADG1211/ADG1212 Truth Table

ADG1211 In	ADG1212 In	Switch Condition
0	1	On
1	0	Off

Table 5. ADG1213 Truth Table

Logic	Switch 1, 4	Switch 2, 3
0	Off	On
1	On	Off

ESD CAUTION
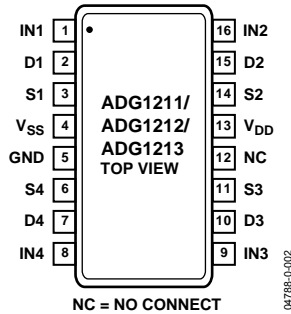
PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS

Figure 2. TSSOP Pin Configuration

ADG1211/ADG1212/ADG1213
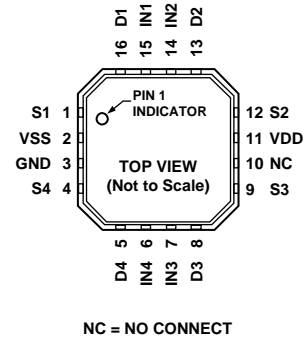
Figure 3. LFCSP Pin Configuration

Table 6. Pin Function Descriptions

Pin No.		Mnemonic	Function
TSSOP	**LFCSP**		
1	15	IN1	Logic Control Input.
2	16	D1	Drain Terminal. Can be an input or output.
3	1	S1	Source Terminal. Can be an input or output.
4	2	V_{SS}	Most Negative Power Supply Potential.
5	3	GND	Ground (0 V) Reference.
6	4	S4	Source Terminal. Can be an input or output.
7	5	D4	Drain Terminal. Can be an input or output.
8	6	IN4	Logic Control Input.
0	7	IN3	Logic Control Input.
10	8	D3	Drain Terminal. Can be an input or output.
11	9	S3	Source Terminal. Can be an input or output.
12	10	NC	No Connection.
13	11	V_{DD}	Most Positive Power Supply Potential.
14	12	S2	Source Terminal. Can be an input or output.
15	13	D2	Drain Terminal. Can be an input or output.
16	14	IN2	Logic Control Input.

TERMINOLOGY

I_{DD}
The positive supply current.

I_{SS}
The negative supply current.

V_D (V_S)
The analog voltage on Terminals D and S.

R_{ON}
The ohmic resistance between D and S.

$R_{FLAT(ON)}$
Flatness is defined as the difference between the maximum and minimum value of on resistance, as measured over the specified analog signal range.

I_S (Off)
The source leakage current with the switch off.

I_D (Off)
The drain leakage current with the switch off.

I_D, I_S (On)
The channel leakage current with the switch on.

V_{INL}
The maximum input voltage for Logic 0.

V_{INH}
The minimum input voltage for Logic 1.

I_{INL} (I_{INH})
The input current of the digital input.

C_S (Off)
The off switch source capacitance, measured with reference to ground.

C_D (Off)
The off switch drain capacitance, measured with reference to ground.

C_D, C_S (On)
The on switch capacitance, measured with reference to ground.

C_{IN}
The digital input capacitance.

t_{ON}
The delay between applying the digital control input and the output switching on. See Figure 23.

t_{OFF}
The delay between applying the digital control input and the output switching off.

Charge Injection
A measure of the glitch impulse transferred from the digital input to the analog output during switching.

Off Isolation
A measure of unwanted signal coupling through an off switch.

Crosstalk
A measure of unwanted signal that is coupled through from one channel to another as a result of parasitic capacitance.

Bandwidth
The frequency at which the output is attenuated by 3 dB.

On Response
The frequency response of the on switch.

Insertion Loss
The loss due to the on resistance of the switch.

TYPICAL PERFORMANCE CHARACTERISTICS

Figure 4. On Resistance as a Function of V_D (V_S) for Single Supply

Figure 7. On Resistance as a Function of V_D (V_S) for Different Temperatures, Single Supply

Figure 5. On Resistance as a Function of V_D (V_S) for Dual Supply

Figure 8. On Resistance as a Function of V_D (V_S) for Different Temperatures, Dual Supply

Figure 6. On Resistance as a Function of V_D (V_S) for Different Temperatures, Single Supply

Figure 9. Leakage Currents as a Function of V_D (V_S)

Figure 10. Leakage Currents as a Function of V_D (V_S)

Figure 13. Leakage Currents as a Function of Temperature

Figure 11. Leakage Currents as a Function of V_D (V_S)

Figure 14. Supply Current vs. Input Switching Frequency

Figure 12. Leakage Currents as a Function of Temperature

Figure 15. Charge Injection vs. Source Voltage

TBD

Figure 16. T_{ON}/T_{OFF} Times vs. Temperature

TBD

Figure 18. Crosstalk vs. Frequency

TBD

Figure 17. Off Isolation vs. Frequency

TBD

Figure 19. On Response vs. Frequency

TEST CIRCUITS
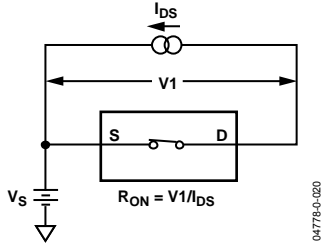
Figure 20. Test Circuit 1—On Resistance
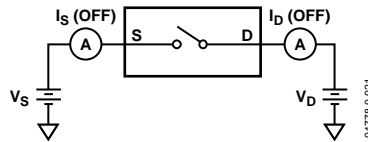
Figure 21. Test Circuit 2—Off Leakage
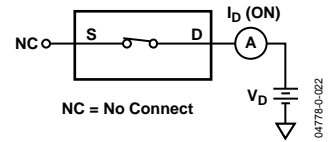
Figure 22. Test Circuit 3 —On Leakage
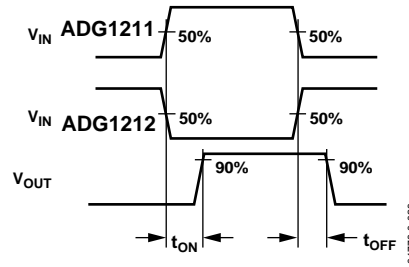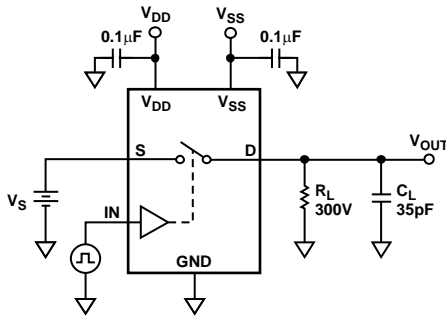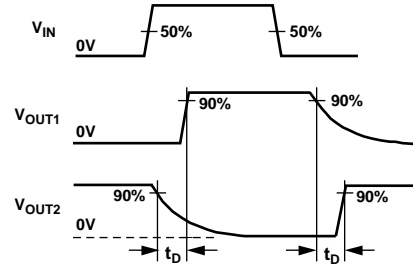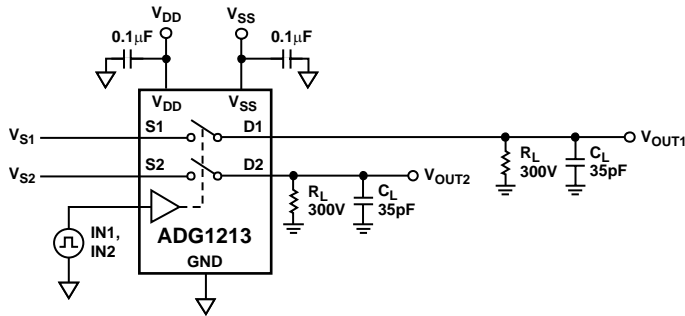

Figure 23. Test Circuit 4—Switching Times

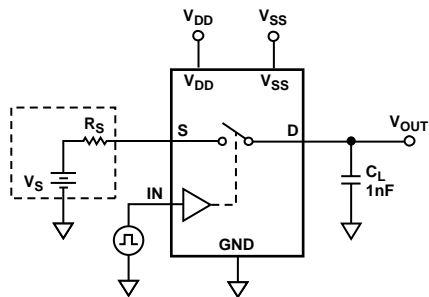

Figure 24. Test Circuit 5—Break Before Make Time Delay
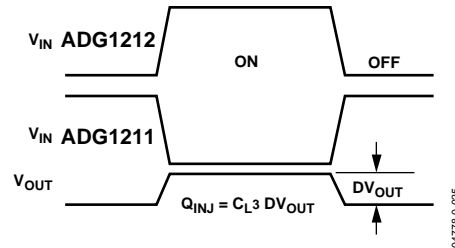
Figure 25. Test Circuit 6—Charge Injection

OFF ISOLATION = 20 LOG $\dfrac{V_{OUT}}{V_S}$
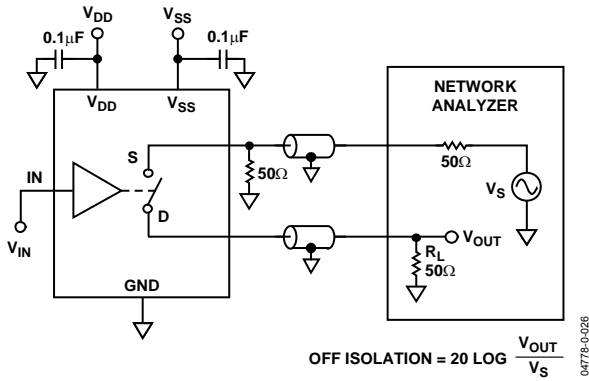
Figure 26. Test Circuit 7—Off Isolation

INSERTION LOSS = 20 LOG $\dfrac{V_{OUT} \text{ WITH SWITCH}}{V_{OUT} \text{ WITHOUT SWITCH}}$
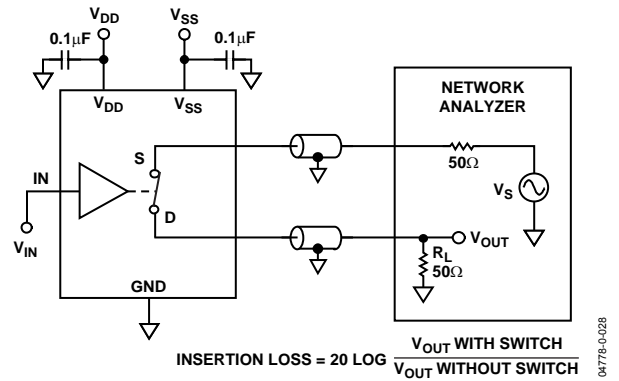
Figure 28. Test Circuit 9—Bandwidth

CHANNEL-TO-CHANNEL CROSSTALK = 20 LOG $\dfrac{V_{OUT}}{V_S}$
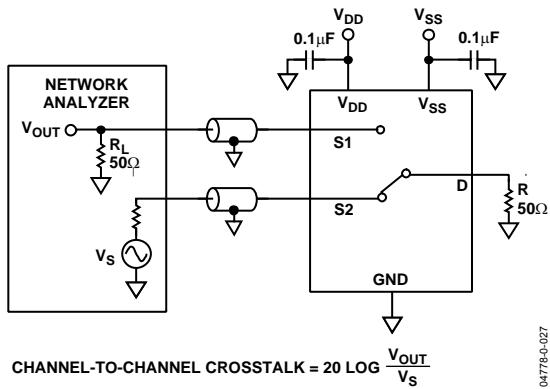
Figure 27. Test Circuit 8—Channel-to-Channel Crosstalk

OUTLINE DIMENSIONS

COMPLIANT TO JEDEC STANDARDS MO-153AB
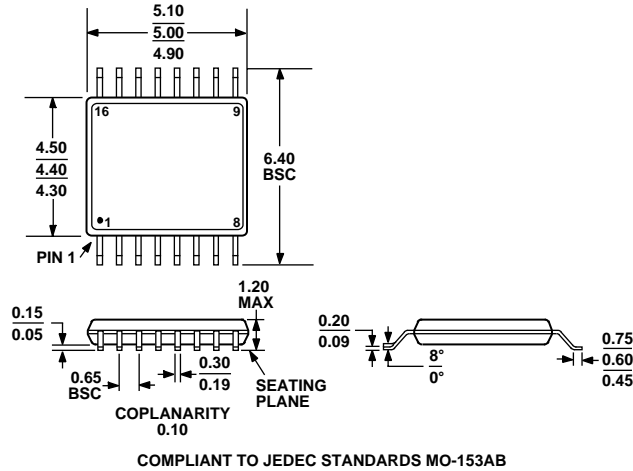
Figure 29. 16-Lead Thin Shrink Small Outline Package [TSSOP]
(RU-16)
Dimensions shown in millimeters
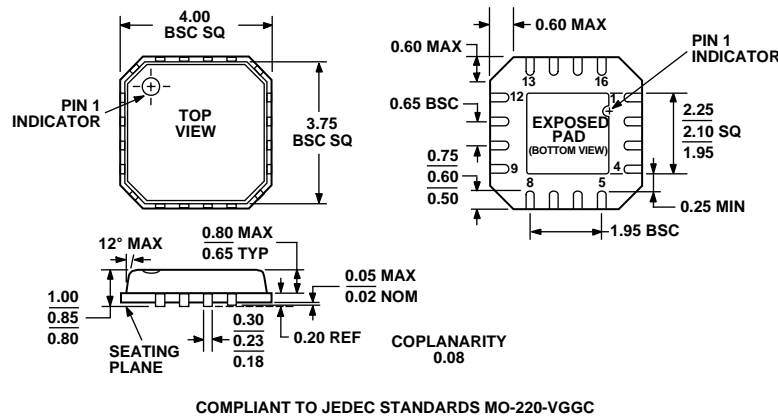

COMPLIANT TO JEDEC STANDARDS MO-220-VGGC

Figure 30. 16-Lead Lead Frame Chip Scale Package [VQ_LFCSP]
4 mm × 4 mm Body, Very Thin Quad
(CP-16-4)
Dimensions shown in millimeters

ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option
ADG1211YRU	−40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1211YCP	−40°C to +125°C	Lead Frame Chip Scale Package (LFCSP)	CP-16-4
ADG1212YRU	−40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1212YCP	−40°C to +125°C	Lead Frame Chip Scale Package (LFCSP)	CP-16-4
ADG1213YRU	−40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1213YCP	−40°C to +125°C	Lead Frame Chip Scale Package (LFCSP)	CP-16-4

NOTES

NOTES

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